# Design and performance of the gaseous beam monitor for the CSR external-target experiment

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The 7th international conference on particle physics and astrophysics

MEPhI, Moscow Oct 22-25, 2024

# Outline

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# **CEE at HIFRL-CSR**

Heavy Ion Research Facility in Lanzhou Cooler-Storage-Ring system



#### CSR External-target Experiment

- Study the properties of nuclear matter at high baryonic density
- Fixed target, with heavy-ion (up to U) beam energy:  $\sim 0.4 1.1 \text{ GeV/u}$
- Maximum event rate: 10<sup>4</sup> s<sup>-1</sup>
- Start operation in 2025



# Beam Monitor of CEE

- Placed upstream of the fixed target in a magnetic shield
- Measure the position of each beam particle
- Offline: vertex reconstruction (combined with TPC and MWDC)
- Online: monitor the beam status
- Main design parameters:
  - Position resolution :  $50 \ \mu m$
  - Minimum time separation of two particles:  $1 \mu s$
  - Sensitive area:  $30 \times 30 \text{ mm}^2$

- Two field cages in a gas vessel
- Custom-designed Topmetal-CEE chip as anode for charge sensing and readout
- Amplification with GEM







### **Detector system**







Field cage v1 : 25 μm Kapton+5 μm Au



Field cage v2 : 2 µm Mylar+100 nm Al

#### Topmetal-CEEv1 chip



The main features of the Topmetal-CEEv1 chip.	
Feature size	130 nm
Chip area	4.2 mm ×19 mm
Number of pixels	$1 \times 180$
Pixel pitch	100 µm
CCE size	1 mm ×89 μm
Shaping time (tunable)	$\sim 0.5~\mu s$ to 2 ms
Peaking time	$\sim 100 \text{ ns}$
Readout scheme	Data-driven readout
Readout time	25 ns/pixel
Amplitude measurement	TOT method

19038 µm





#### Topmetal-CEEv1 chip



#### Topmetal-CEEv2 chip

- Almost same geometry
- Main improvement:
  - Minimum threshold:  $\sim 20 \text{ ke}^- \Rightarrow \sim 5 \text{ ke}^-$
  - Minimum shaping time:  $\sim 1 \ \mu s => \sim 0.5 \ \mu s$





#### **Electronics**





Front-end electronics



Readout and control unit

### Heavy-ion beam test

- Kr at  $\sim$  320 MeV/u
- Rate:  $\sim 10^4 10^6 \text{ s}^{-1}$







Center of geometry Resolution: 47.80 µm



Center of gravity Resolution: 41.85 µm

#### Laser test

• 266 nm pulsed laser





Amplitude [700 e<sup>-</sup>]



Events normalized to unit 0.14 E<sub>drift</sub> = 300 V/cm = 2.5 cm 0.12 L<sub>drift</sub> = 3.3 cm L<sub>drift</sub> = 4.3 cm 0.1 0.08 0.06 0.04 0.02 0 120 140 160 180 200 220 240 260 280 300 Drift time + Laser delay [25 ns] Drift time + Laser delay [µs] E<sub>drift</sub> = 300 V/cm  $V_{Drift} = 0.728 \pm 0.003 \text{ cm/}\mu\text{s}$ 2 2.5 0 0.5 1 1.5 3 3.5 4 4.5 5 Drift distance [cm] 14 Std. Dev. of Drift time [ns] E<sub>drift</sub> = 300 V/cm 13 12 11 10 9 Resolution: 9-13 ns 7<u>1.</u> 1.5 2 2.5 3 3.5 4 4.5

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Drift distance [cm]

Time [25 ns]

# Summary and Outlook

- Gaseous beam monitor, part of the CEE experiment, is under development.
- It features Topmetal-CEE chips for charge sensing and readout in the gas, with GEM for amplification.
- Complete detector system, including the gas detector, front-end electronics, and readout and control electronics, have been developed.
- Preliminary results from heavy-ion beam and laser tests showed a spatial resolution better than 50  $\mu$ m and a time resolution better than 15 ns.